SCLS091B - DECEMBER 1982 - REVISED MAY 1997

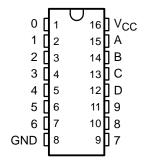
- Full Decoding of Input Logic
- All Outputs Are High for Invalid BCD Conditions
- Also for Applications as 3-Line to 8-Line Decoders
- Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W)
 Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J)
 300-mil DIPs

description

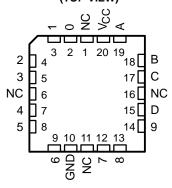
These monolithic decimal decoders consist of eight inverters and ten 4-input NAND gates. The inverters are connected in pairs to make BCD input data available for decoding by the NAND gates. Full decoding of valid input logic ensures that all inputs remain off for all invalid input conditions.

The SN54HC42 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74HC42 is characterized for operation from -40°C to 85°C.

SN54HC42...J OR W PACKAGE SN74HC42...D OR N PACKAGE (TOP VIEW)



SN54HC42...FK PACKAGE (TOP VIEW)



NC - No internal connection

FUNCTION TABLE

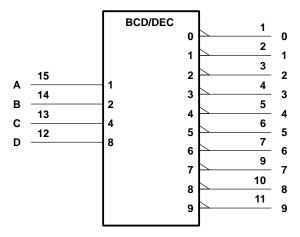
NO.	INPUTS				OUTPUTS									
NO.	D	С	В	Α	0	1	2	3	4	5	6	7	8	9
0	L	L	L	L	L	Н	Н	Н	Н	Н	Н	Н	Н	Н
1	L	L	L	Н	Н	L	Н	Н	Н	Н	Н	Н	Н	Н
2	L	L	Н	L	Н	Н	L	Н	Н	Н	Н	Н	Н	Н
3	L	L	Н	Н	Н	Н	Н	L	Н	Н	Н	Н	Н	Н
4	L	Н	L	L	Н	Н	Н	Н	L	Н	Н	Н	Н	Н
5	L	Н	L	Н	Н	Н	Н	Н	Н	L	Н	Н	Н	Н
6	L	Н	Н	L	Н	Н	Н	Н	Н	Н	L	Н	Н	Н
7	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	L	Н	Н
8	Н	L	L	L	Н	Н	Н	Н	Н	Н	Н	Н	L	Н
9	Н	L	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	L
	Н	L	Н	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н
	Н	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н
Invalid	Н	Н	L	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н
invalid	Н	Н	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н
	Н	Н	Н	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н
	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н



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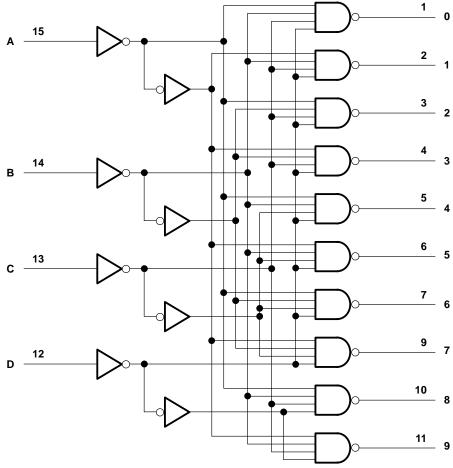


logic symbol†



 $^{^\}dagger$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, and W packages.

logic diagram (positive logic)



Pin numbers shown are for the D, J, N, and W packages.



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absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±25 mA
Continuous current through V _{CC} or GND	±50 mA
Package thermal impedance, θ _{JA} (see Note 2): D package	113°C/W
*···	78°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

			S	SN54HC42			SN74HC42			
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
VCC	Supply voltage		2	5	6	2	5	6	V	
		V _{CC} = 2 V	1.5			1.5				
٧ _{IH}	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			3.15			V	
		V _{CC} = 6 V	4.2			4.2				
		V _{CC} = 2 V	0		0.5	0		0.5		
VIL	Low-level input voltage	V _{CC} = 4.5 V	0		1.35	0		1.35	V	
		VCC = 6 V	0		1.8	0		1.8		
٧١	Input voltage		0		VCC	0		VCC	V	
٧o	Output voltage		0		VCC	0		VCC	V	
		V _{CC} = 2 V	0		1000	0		1000		
t _t	Input transition (rise and fall) time	V _{CC} = 4.5 V	0		500	0		500	ns	
		V _{CC} = 6 V	0		400	0		400		
TA	Operating free-air temperature		-55		125	-40		85	°C	



^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Vaa	Т	A = 25°C	;	SN54HC42		SN74HC42		UNIT
PARAMETER			vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONII
			2 V	1.9	1.998		1.9		1.9		V
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		
		$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
	VI = VIH or VIL	I _{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	V
			4.5 V		0.001	0.1		0.1		0.1	
VOL			6 V		0.001	0.1		0.1		0.1	
		I _{OL} = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
		$I_{OL} = 5.2 \text{ mA}$	6 V		0.15	0.26		0.4		0.33	
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
^I CC	$V_I = V_{CC}$ or 0,	I _O = 0	6 V			8		160		80	μΑ
C _i			2 V to 6 V		3	10		10		10	pF

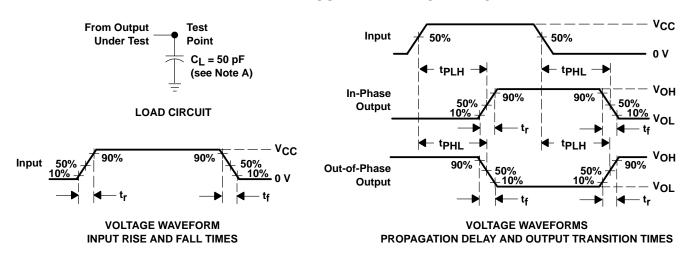
switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	V	T _A = 25°C			SN54HC42		SN74HC42		UNIT
PARAMETER	(INPUT)	(OUTPUT)	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONIT
	A, B, C, or D	0–9	2 V		65	150		225		190	ns
tpd			4.5 V		18	30		45		38	
			6 V		14	26		38		32	
		Any	2 V		28	75		110		95	
t _t			4.5 V		8	15		22		19	ns
			6 V		7	13		19		16	

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load	39	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f = 6 \ ns$, $t_f = 6 \ ns$.
- C. The outputs are measured one at a time with one input transition per measurement.
- D. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

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